



**MICROCHIP**

# **QUALIFICATION PLAN**

**PCN #: IIRA-19HYJU812**

**Date:  
Dec 18, 2013**

**Qualification of selected products available in the 28L  
SPDIP package with palladium coated copper (PdCu)  
bond wire at MMT (ALPH) assembly site.**

Distribution

Surasit P.  
Mitchell R.  
Wichai K.  
Arnel M.

Rangsun K.  
F. Chen  
S. Melby  
Chaweng W.

Microchip Technology (Thailand) Co., Ltd.  
14 Moo 1 T. Wangtakien A. Muangchacherngsao,  
Chacherngsao, Thailand, 24000  
Tel. (6638) 857119-45, 857311-19 ext. 1231  
Fax (6638) 857149-50

**Purpose:** \_\_\_\_\_ Qualification of selected products available in the 28L SPDIP package with palladium coated copper (PdCu) bond wire at MMT (ALPH) assembly site.

**MP code:** \_\_\_\_\_ A5AF14M3XE04

**Part No.:** \_\_\_\_\_ PIC16F876-04E/SP

**BD No:** \_\_\_\_\_ BDM-000418 rev.A

**CCB No:** \_\_\_\_\_ 1361.01

**Package:**

**Type** \_\_\_\_\_ 28L SPDIP

**Width or Size** \_\_\_\_\_ 300 mils

**Die thickness:** \_\_\_\_\_ 15 mils

**Die size:** \_\_\_\_\_ 179.20 x 199.60 mils

**Lead frame:**

**Paddle size:** \_\_\_\_\_ 196 x 300 mils (Samsung-Korea)

**Material** \_\_\_\_\_ C194

**Surface** \_\_\_\_\_ Ring Ag on Paddle

**Process** \_\_\_\_\_ Stamped

**Lead Lock** \_\_\_\_\_ No

**Part Number** \_\_\_\_\_ TBD

**Treatment** \_\_\_\_\_ None

**Wire:**

**Material** \_\_\_\_\_ PdCu (Nippon-Japan)

**Die Attach Epoxy:**

**Part Number** \_\_\_\_\_ CRM-1064L (Sumitomo-Singapore)

**Conductive** \_\_\_\_\_ Yes

**Mold Compound:** \_\_\_\_\_ GE800 (Hitachi-Malaysia)

**Reliability Test plan:** \_\_\_\_\_ See attached, STD Package Reliability Test plan on each package.

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	Special Instructions
Wire Bond Pull - WBP	Mil. Std. 883-2011	5	0	1	5	0 fails after TC	5	30 bonds from a minimum of 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001	5	0	1	5	0	5	30 bonds from a minimum of 5 devices.
Wire Sweep		5	1	3	15			Required for any reduction in wire bond thickness.
External Visual	Mil. Std. 883-2009/2010	All devices prior to submission for qualification testing	0	3	ALL	0	5	
HTSL (High Temp Storage Life)	+175 C for 504 hours or 150°C for 1008 hrs. Electrical test pre and post stress at +25C and hot temp.	45	5	1	50	0	10	Must be in progress at time of package release to production, but completion is not required for release to production. For hot temp testing, pre/post test 1 lot at 85°C and 125°C (if applicable).
HAST	+130°C/85% RH for 96 hours. Electrical test pre and post stress at +25°C and hot temp.	77	5	3	246	0	10	Spares should be properly identified. Use the parts which have gone through Pre-conditioning. For hot temp testing, pre/post test 1 lot at 85°C and 125°C (if applicable).
Unbiased HAST	+130°C/85% RH for 96 hrs. Electrical test pre and post stress at +25°C.	77	5	3	246	0	10	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
Temp Cycle	-65°C to +150°C for 500 cycles. Electrical test pre and post stress at hot temp; 3 gram force WBP, on 5 devices from 1 lot, Test by following readpoint TC50,TC250 and TC 500.	77	5	3	246	0	15	Spares should be properly identified. Use the parts which have gone through Pre-conditioning. For hot temp testing, pre/post test 1 lot at 85°C and 125°C (if applicable).